

## Si4925DY

# Dual P-Channel, Logic Level, PowerTrench MOSFET

### **General Description**

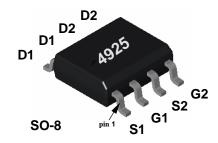
These P-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

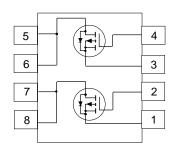
These devices are well suited for notebook computer applications: load switching and power management, battery charging circuits, and DC/DC conversion.

### **Features**

- Low gate charge (14.5nC typical).
- High performance trench technology for extremely low R<sub>DS/ONI</sub>.
- High power and current handling capability.







## **Absolute Maximum Ratings** T<sub>0</sub> = 25°C unless otherwise noted

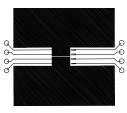
Symbol	Parameter	Si4925DY	Units	
V <sub>DSS</sub>	Drain-Source Voltage	-30	V	
V <sub>GSS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Drain Current - Continuous (Note 1a)	-6	A	
	- Pulsed	-20		
P <sub>D</sub>	Power Dissipation for Dual Operation	2	W	
	Power Dissipation for Single Operation (Note 1a)	1.6		
	(Note 1b)	1		
	(Note 1c)	0.9		
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to 150	°C	
THERMA	L CHARACTERISTICS		•	
$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W	
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W	

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAF	RACTERISTICS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
$\Delta$ BV <sub>DSS</sub> / $\Delta$ T <sub>J</sub>	Breakdown Voltage Temp. Coefficient	$I_D = -250 \mu\text{A}$ , Referenced	to 25 °C		-21		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$				-1	μA
			T <sub>J</sub> = 55°C			-10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 16 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -16 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHARA	ACTERISTICS (Note 2)	<u>.</u>			•		•
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.7	-3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25 °C			4		mV/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -6 \text{ A}$			0.025	0.032	Ω
25(21.4)			T <sub>J</sub> =125°C		0.033	0.051	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$			0.034	0.045	
I <sub>D(ON)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V}, \ V_{DS} = -5 \text{ V}$		-20			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -6 \text{ A}$			16		S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1540		pF
C <sub>oss</sub>	Output Capacitance				400		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				170		pF
SWITCHIN	G CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DS} = -15 \text{ V}, \ I_{D} = -1 \text{ A}$ $V_{GEN} = -10 \text{ V}, R_{GEN} = 6 \Omega$			13	24	ns
t,	Turn - On Rise Time				22	35	ns
t <sub>D(off)</sub>	Turn - Off Delay Time				47	75	ns
t,	Turn - Off Fall Time				18	30	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -6 \text{ A},$			14.5	20	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = -5 V			4		nC
$Q_{gd}$	Gate-Drain Charge				5		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND MA	XIMUM RATINGS					
I <sub>s</sub>	Maximum Continuous Drain-Source Diode Forward Current					-1.3	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.3 \text{ A} \text{ (Note 2)}$			-0.73	-1.2	V

#### Notes:

<sup>1.</sup>  $R_{g,u}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{g,C}$  is guaranteed by design while  $R_{gCA}$  is determined by the user's board design.



a. 78°C/W on a 0.5 in² pad of 2oz copper.



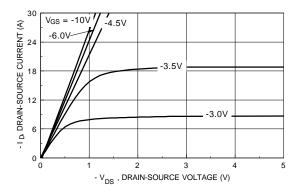


c. 135°C/W on a 0.003 in² pad of 2oz copper.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

## **Typical Electrical Characteristics**



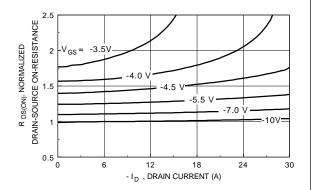
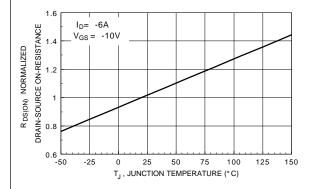


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Dain Current and Gate Voltage.



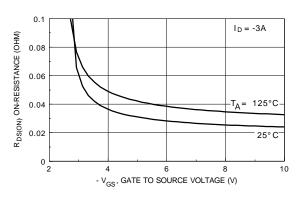
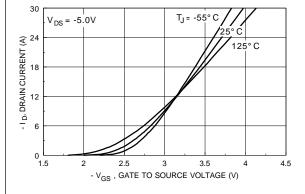


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



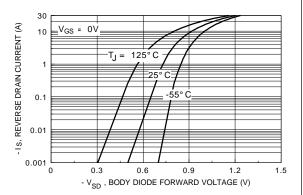
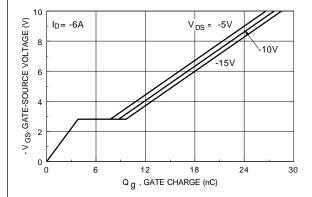


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage
Variation with Source Current
and Temperature.

## **Typical Electrical Characteristics** (continued)



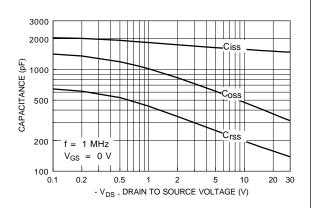
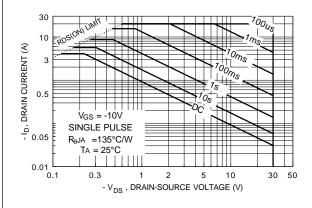


Figure 7. Gate Charge Characteristics.





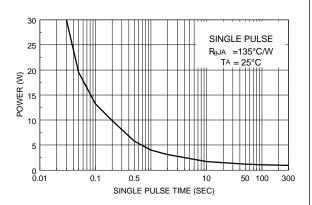
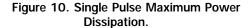


Figure 9. Maximum Safe Operating Area.



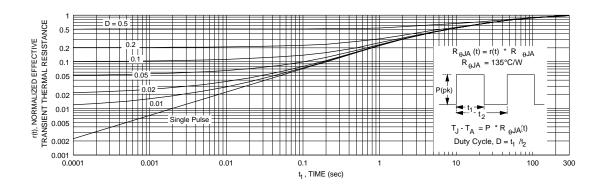


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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